

**Notice of References Cited**

Application/Control No.

10/549,926

Applicant(s)/Patent Under  
Reexamination  
GRUDIN ET AL.

Examiner

Vuthe Siek

Art Unit

2825

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0101573	06-2003	Nelson et al.	29/612
*	B	US-2003/0062984	04-2003	Ito et al.	338/25
*	C	US-2002/0113127	08-2002	Takeuchi et al.	235/462.25
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	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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